

# HUF76629D3, HUF76629D3S

Data Sheet

December 2001

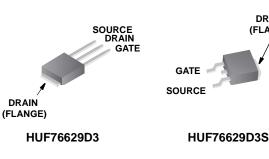
# 20A, 100V, 0.054 Ohm, N-Channel, Logic Level UltraFET® Power MOSFET



JEDEC TO-252AA

DRAIN

(FLANGE)



# Symbol



# UltraFIET

# Features

- Ultra Low On-Resistance
  - $r_{DS(ON)} = 0.052\Omega, V_{GS} = 10V$
  - $r_{DS(ON)} = 0.054\Omega, V_{GS} = 5V$
- Simulation Models
  - Temperature Compensated PSPICE® and SABER™ Electriecal Models
  - Spice and SABER Thermal Impedance Models
  - www.fairchildsemi.com
- Peak Current vs Pulse Width Curve
- UIS Rating Curve
- Switching Time vs R<sub>GS</sub> Curves

# **Ordering Information**

| PART NUMBER | PACKAGE  | BRAND  |
|-------------|----------|--------|
| HUF76629D3  | TO-251AA | 76629D |
| HUF76629D3S | TO-252AA | 76629D |

NOTE: When ordering, use the entire part number. Add the suffix T to obtain the variant in tape and reel, e.g., HUF76629D3ST.

## Absolute Maximum Ratings T<sub>C</sub> = 25°C, Unless Otherwise Specified

|   | HUF76629D3, HUF76629D3S | UNITS             |
|---|-------------------------|-------------------|
| Drain to Source Voltage (Note 1) V <sub>DSS</sub>   | 100                     | V                 |
| Drain to Gate Voltage (R <sub>GS</sub> = 20kΩ) (Note 1)   | 100                     | V                 |
| Gate to Source Voltage V <sub>GS</sub>  | ±16                     | V                 |
| Drain Current   |                         |                   |
| Continuous (T <sub>C</sub> = 25 <sup>o</sup> C, V <sub>GS</sub> = 5V) $\dots$ I <sub>D</sub>    | 20                      | A                 |
| Continuous (T <sub>C</sub> = 25 <sup>o</sup> C, V <sub>GS</sub> = 10V) (Figure 2)               | 20                      | A                 |
| Continuous (T <sub>C</sub> = 100 <sup>o</sup> C, V <sub>GS</sub> = 5V) $\dots$ I <sub>D</sub>   | 20                      | A                 |
| Continuous (T <sub>C</sub> = $100^{\circ}$ C, V <sub>GS</sub> = 4.5V) (Figure 2) I <sub>D</sub> | 20                      | A                 |
| Pulsed Drain Current  | Figure 4                |                   |
| Pulsed Avalanche RatingUIS  | Figures 6, 17, 18       |                   |
| Power Dissipation   | 110                     | W                 |
| Derate Above 25°C   | 0.74                    | W/ <sup>o</sup> C |
| Operating and Storage Temperature   | -55 to 175              | °C                |
| Maximum Temperature for Soldering   |                         |                   |
| Leads at 0.063in (1.6mm) from Case for 10s.   | 300                     | °C                |
| Package Body for 10s, See Techbrief TB334   | 260                     | °C                |

NOTES:

1.  $T_J = 25^{\circ}C$  to  $150^{\circ}C$ .

**CAUTION:** Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

#### Product reliability information can be found at http://www.fairchildsemi.com/products/discrete/reliability/index.html For severe environments, see our Automotive HUFA series.

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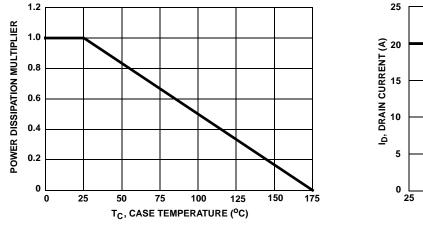
#### PARAMETER SYMBOL **TEST CONDITIONS** UNITS MIN TYP MAX OFF STATE SPECIFICATIONS $I_D = 250\mu A, V_{GS} = 0V$ (Figure 12) 100 V Drain to Source Breakdown Voltage BV<sub>DSS</sub> $I_D = 250\mu A$ , $V_{GS} = 0V$ , $T_C = -40^{\circ}C$ (Figure 12) V 90 -- $V_{DS} = 95\overline{V}, V_{GS} = 0\overline{V}$ Zero Gate Voltage Drain Current IDSS 1 μΑ -- $V_{DS} = 90V, V_{GS} = 0V, T_{C} = 150^{\circ}C$ 250 μΑ --±100 Gate to Source Leakage Current IGSS $V_{GS} = \pm 16V$ nA --**ON STATE SPECIFICATIONS** Gate to Source Threshold Voltage $V_{GS} = V_{DS}, I_{D} = 250 \mu A$ (Figure 11) 3 V V<sub>GS(TH)</sub> 1 -Drain to Source On Resistance I<sub>D</sub> = 20A, V<sub>GS</sub> = 10V (Figures 9, 10) 0.0415 0.052 0 rDS(ON) - $I_{D} = 20A, V_{GS} = 5V$ (Figure 9) 0.046 0.054 Ω I<sub>D</sub> = 20A, V<sub>GS</sub> = 4.5V (Figure 9) \_ 0.047 0.055 Ω THERMAL SPECIFICATIONS Thermal Resistance Junction to Case TO-251AA and TO-252AA °C/W 1.36 $R_{\theta JC}$ \_ -Thermal Resistance Junction to $\mathsf{R}_{\theta\mathsf{J}\mathsf{A}}$ 100 °C/W --Ambient SWITCHING SPECIFICATIONS (VGS = 4.5V) Turn-On Time $V_{DD} = 50V, I_D = 20A$ 190 -ns tON $V_{GS} = 4.5V, R_{GS} = 6.8\Omega$ Turn-On Delay Time 11 ns td(ON) -(Figures 15, 21, 22) **Rise Time** 114 tr \_ ns Turn-Off Delay Time -38 ns td(OFF) Fall Time 60 ns tf -Turn-Off Time 145 \_ tOFF ns SWITCHING SPECIFICATIONS (VGS = 10V) Turn-On Time V<sub>DD</sub> = 50V, I<sub>D</sub> = 20A 50 ns <sup>t</sup>ON $V_{GS} = 10V, R_{GS} = 8.2\Omega$ Turn-On Delav Time 6.8 td(ON) \_ ns (Figures 16, 21, 22) Rise Time 28 ns tr --Turn-Off Delay Time 67 ns td(OFF) Fall Time 60 t<sub>f</sub> \_ \_ ns Turn-Off Time 190 -ns tOFF GATE CHARGE SPECIFICATIONS $V_{DD} = 50\overline{V},$ **Total Gate Charge** Q<sub>g(TOT)</sub> $V_{GS} = 0V$ to 10V-38 46 nC $I_{D} = 20A$ , Gate Charge at 5V $V_{GS} = 0V$ to 5V 21 25 nC $Q_{q(5)}$ - $I_{a(REF)} = 1.0 mA$ Threshold Gate Charge $V_{GS} = 0V$ to 1V1.2 Q<sub>g(TH)</sub> -1.6 nC (Figures 14, 19, 20) Gate to Source Gate Charge 3.3 nC Qgs --Gate to Drain "Miller" Charge 10 nC $\mathsf{Q}_{\mathsf{gd}}$ -CAPACITANCE SPECIFICATIONS Input Capacitance $V_{DS} = 25V, V_{GS} = 0V,$ CISS -1285 pF f = 1MHz**Output Capacitance** COSS 270 pF --(Figure 13) pF **Reverse Transfer Capacitance** 65 C<sub>RSS</sub> \_ -

### **Electrical Specifications** $T_C = 25^{\circ}C$ , Unless Otherwise Specified

#### Source to Drain Diode Specifications

| PARAMETER                     | SYMBOL          | TEST CONDITIONS                                       | MIN | ТҮР | MAX  | UNITS |
|-------------------------------|-----------------|---|-----|-----|------|-------|
| Source to Drain Diode Voltage | V <sub>SD</sub> | I <sub>SD</sub> = 20A                                 | -   | -   | 1.25 | V     |
|                               |                 | I <sub>SD</sub> = 10A                                 | -   | -   | 1.00 | V     |
| Reverse Recovery Time         | t <sub>rr</sub> | I <sub>SD</sub> = 20A, dI <sub>SD</sub> /dt = 100A/μs | -   | -   | 110  | ns    |
| Reverse Recovered Charge      | Q <sub>RR</sub> | $I_{SD}$ = 20A, dI <sub>SD</sub> /dt = 100A/µs        | -   | -   | 370  | nC    |

# **Typical Performance Curves**





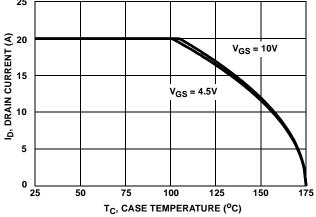
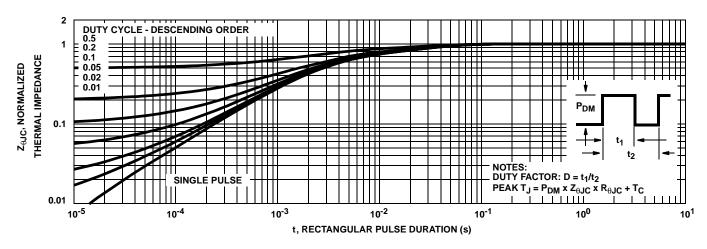
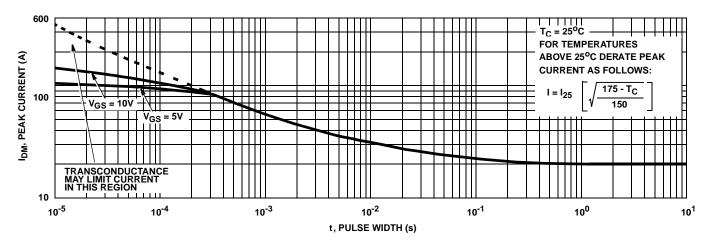


FIGURE 2. MAXIMUM CONTINUOUS DRAIN CURRENT vs CASE TEMPERATURE









# Typical Performance Curves (Continued)

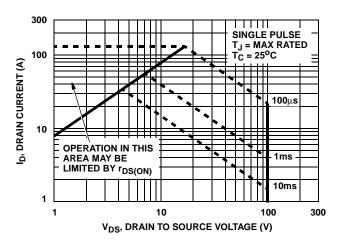


FIGURE 5. FORWARD BIAS SAFE OPERATING AREA

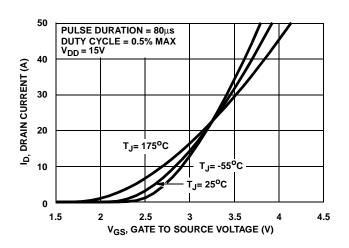
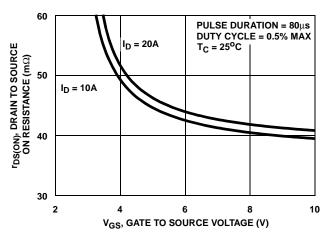
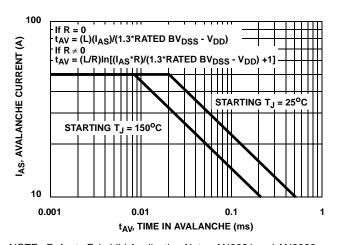


FIGURE 7. TRANSFER CHARACTERISTICS

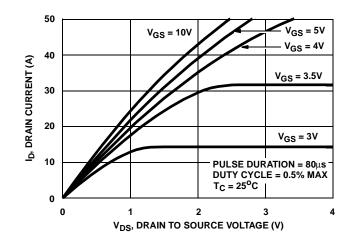






NOTE: Refer to Fairchild Application Notes AN9321 and AN9322. FIGURE 6. UNCLAMPED INDUCTIVE SWITCHING

CAPABILITY





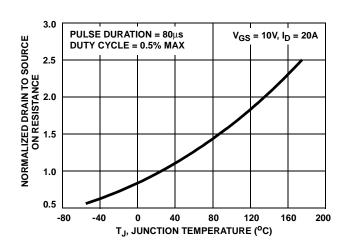
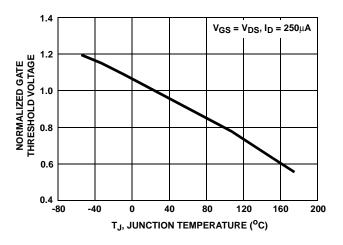


FIGURE 10. NORMALIZED DRAIN TO SOURCE ON RESISTANCE vs JUNCTION TEMPERATURE

# Typical Performance Curves (Continued)





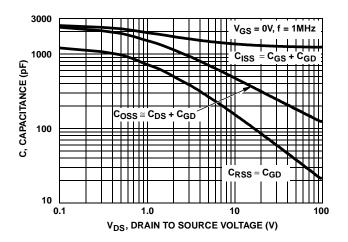


FIGURE 13. CAPACITANCE vs DRAIN TO SOURCE VOLTAGE

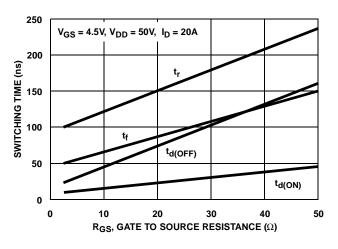


FIGURE 15. SWITCHING TIME vs GATE RESISTANCE

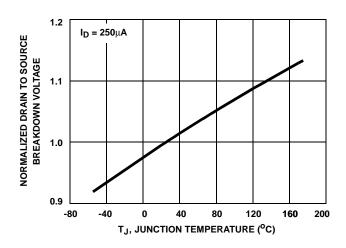
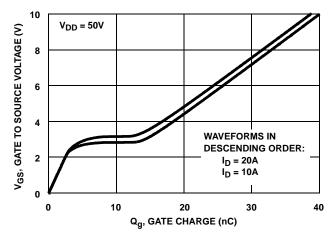


FIGURE 12. NORMALIZED DRAIN TO SOURCE BREAKDOWN VOLTAGE vs JUNCTION TEMPERATURE



NOTE: Refer to Fairchild Application Notes AN7254 and AN7260. FIGURE 14. GATE CHARGE WAVEFORMS FOR CONSTANT GATE CURRENT

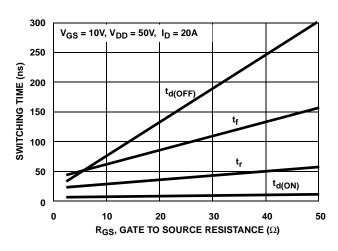


FIGURE 16. SWITCHING TIME vs GATE RESISTANCE

# Test Circuits and Waveforms

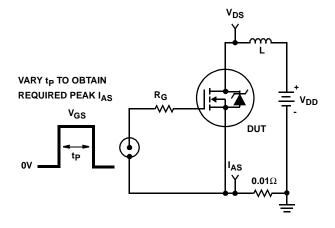


FIGURE 17. UNCLAMPED ENERGY TEST CIRCUIT

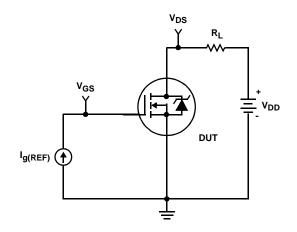


FIGURE 19. GATE CHARGE TEST CIRCUIT

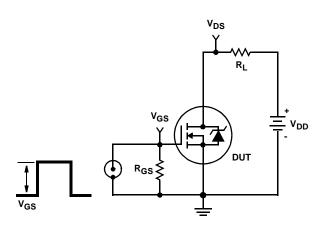


FIGURE 21. SWITCHING TIME TEST CIRCUIT

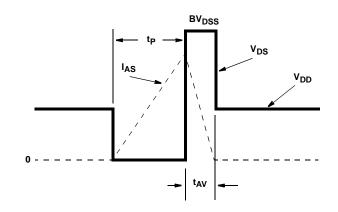


FIGURE 18. UNCLAMPED ENERGY WAVEFORMS

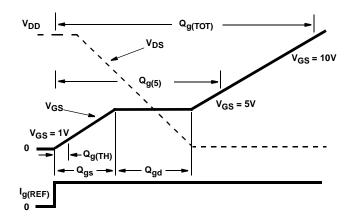
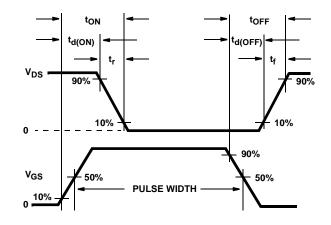


FIGURE 20. GATE CHARGE WAVEFORMS

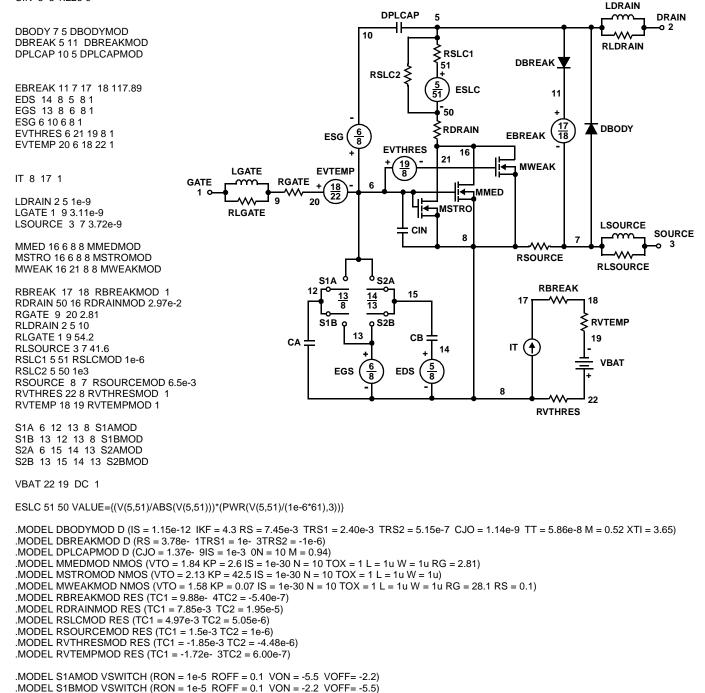




# **PSPICE Electrical Model**

.SUBCKT HUF76629D3 2 1 3 ; rev 30 July 1999

CA 12 8 2.32e-9 CB 15 14 2.32e-9 CIN 6 8 1.22e-9



#### .ENDS

NOTE: For further discussion of the PSPICE model, consult A New PSPICE Sub-Circuit for the Power MOSFET Featuring Global Temperature Options; IEEE Power Electronics Specialist Conference Records, 1991, written by William J. Hepp and C. Frank Wheatley.

.MODEL S2AMOD VSWITCH (RON = 1e-5 ROFF = 0.1 VON = -1.1 VOFF= 0.5) .MODEL S2BMOD VSWITCH (RON = 1e-5 ROFF = 0.1 VON = 0.5 VOFF= -1.1)

# SABER Electrical Model

#### REV 30 July 1999 template huf76629d3 n2,n1,n3 electrical n2,n1,n3 var i iscl d..model dbodymod = (is = 1.15e-12, cjo = 1.14e-9, tt = 5.86e-8, xti = 3.65, m = 0.52) d..model dbreakmod = () d..model dplcapmod = (cjo = 1.37e-9, is = 1e-30, n = 10, m = 0.94) m.model mmedmod = (type=\_n, vto = 1.84, kp = 2.6, is = 1e-30, tox = 1) m..model mstrongmod = (type=\_n, vto = 2.13, kp = 42.5, is = 1e-30, tox = 1) m..model mweakmod = (type=\_n, vto = 1.58, kp = 0.07, is = 1e-30, tox = 1) LDRAIN sw\_vcsp..model s1amod = (ron = 1e-5, roff = 0.1, von = -5.5, voff = -2.2) DPLCAP 5 DRAIN sw vcsp..model s1bmod = (ron =1e-5, roff = 0.1, von = -2.2, voff = -5.5) o 2 sw\_vcsp...model s2amod = (ron = 1e-5, roff = 0.1, von = -1.1, voff = 0.5) 10 RLDRAIN sw\_vcsp..model s2bmod = (ron = 1e-5, roff = 0.1, von = 0.5, voff = -1.1) RSLC1 RDBREAK 51 c.ca n12 n8 = 2.32e-9 RSLC2 ≥ 72 c.cb n15 n14 = 2.32e-9 RDBODY ISCL c.cin n6 n8 = 1.22e-9 DBREAK 50 d.dbody n7 n71 = model=dbodymod 71 d.dbreak n72 n11 = model=dbreakmod 6 8 ESG 11 d.dplcap n10 n5 = model=dplcapmod EVTHRES 16 21 19 8 MWEAK i.it n8 n17 = 1 4 LGATE EVTEMP DBODY RGATE GATE 6 EBREAK I.Idrain n2 n5 = 1e-9 MMED 1 C I 22 9 $\sim$ 20 I.loate n1 n9 = 3.11e-9 -1MSTR RLGATE l.lsource n3 n7 = 3.72e-9 LSOURCE CIN SOURCE 8 m.mmed n16 n6 n8 n8 = model=mmedmod, l=1u, w=1u 3 m.mstrong n16 n6 n8 n8 = model=mstrongmod, l=1u, w=1u RSOURCE m.mweak n16 n21 n8 n8 = model=mweakmod, l=1u, w=1u RLSOURCE S1A os2A res.rbreak n17 n18 = 1, tc1 = 9.88e-4, tc2 = -5.40e-7 RBREAK <u>13</u> 8 <u>14</u> 13 15 res.rdbody n71 n5 = 7.45e-3, tc1 = 2.40e-3, tc2 = 5.15e-7 17 18 res.rdbreak n72 n5 = 3.78e-1, tc1 = 1.00e-3, tc2 = -1.00e-6 RVTEMP res.rdrain n50 n16 = 2.97e-2, tc1 = 7.85e-3, tc2 = 1.95e-5 o S2B S1B res.rgate n9 n20 = 2.81 13 CB 19 CA res.rldrain n2 n5 = 10 IT (♠ 14 res.rlgate n1 n9 = 54.2 VBAT res.rlsource n3 n7 = 41.6<u>6</u> 8 5 EGS EDS res.rslc1 n5 n51 = 1e-6, tc1 = 4.97e-3, tc2 = 5.05e-6 8 res.rslc2 n5 n50 = 1e3 22 res.rsource n8 n7 = 6.5e-3, tc1 = 1.5e-3, tc2 = 1e-6 RVTHRES res.rvtemp n18 n19 = 1, tc1 = -1.72e-3, tc2 = 6.00e-7 res.rvthres n22 n8 = 1, tc1 = -1.85e-3, tc2 = -4.48e-6 spe.ebreak n11 n7 n17 n18 = 117.89 spe.eds n14 n8 n5 n8 = 1 spe.egs n13 n8 n6 n8 = 1 spe.esg n6 n10 n6 n8 = 1 spe.evtemp n20 n6 n18 n22 = 1 spe.evthres n6 n21 n19 n8 = 1 sw\_vcsp.s1a n6 n12 n13 n8 = model=s1amod sw\_vcsp.s1b n13 n12 n13 n8 = model=s1bmod sw\_vcsp.s2a n6 n15 n14 n13 = model=s2amod sw\_vcsp.s2b n13 n15 n14 n13 = model=s2bmod v.vbat n22 n19 = dc=1 equations { i (n51->n50) +=iscl iscl: v(n51,n50) = ((v(n5,n51)/(1e-9+abs(v(n5,n51))))\*((abs(v(n5,n51)\*1e6/61))\*\* 3))

# SPICE Thermal Model

#### REV 26 July 1999

#### HUF76629D3

CTHERM1 th 6 2.45e-3 CTHERM2 6 5 8.15e-3 CTHERM3 5 4 7.40e-3 CTHERM4 4 3 7.45e-3 CTHERM5 3 2 1.01e-2 CTHERM6 2 tl 7.49e-2

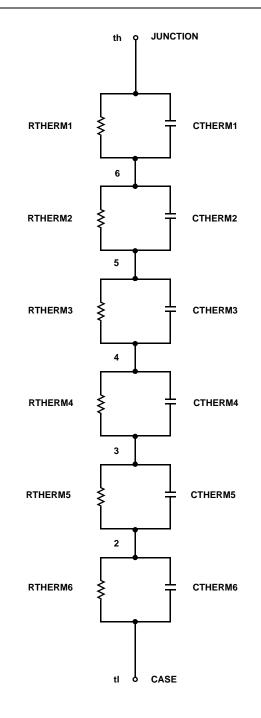
RTHERM1 th 6 9.00e-3 RTHERM2 6 5 1.80e-2 RTHERM3 5 4 9.15e-2 RTHERM4 4 3 2.43e-1 RTHERM5 3 2 3.50e-1 RTHERM6 2 tl 3.62e-1

# SABER Thermal Model

SABER thermal model HUF76629D3

template thermal\_model th tl thermal\_c th, tl { ctherm.ctherm1 th 6 = 2.45e-3 ctherm.ctherm2 6 5 = 8.15e-3 ctherm.ctherm3 5 4 = 7.40e-3 ctherm.ctherm4 4 3 = 7.45e-3 ctherm.ctherm5 3 2 = 1.01e-2 ctherm.ctherm6 2 tl = 7.49e-2

rtherm.rtherm1 th 6 = 9.00e-3 rtherm.rtherm2 6 5 = 1.80e-2 rtherm.rtherm3 5 4 = 9.15e-2 rtherm.rtherm4 4 3 = 2.43e-1 rtherm.rtherm5 3 2 = 3.50e-1 rtherm.rtherm6 2 tl = 3.62e-1 }



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